Search Notes		

Application/Control No.	Applicant(s)/Patent und Reexamination	der
10/658,252	MAEZAWA ET AL.	
Examiner	Art Unit	
Shun Lee	2884	

	SEARCHED			
Class	Subclass	Date	Examiner	
250	484.4	9/30/2005	SL	
252	301.4H	9/30/2005	SL	
Above	UPDATED	6/7/2006	SL	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, IBM_TDB) - See Search History Printout	6/7/2006	SL
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